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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>		ATTY DOCKET NO. YMOR:233		SERIAL NO. New Application <b>10/018477</b>			
		APPLICANT Kazuhiro TAKEUCHI					
		FILING DATE December 19, 2001				GROUP	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>MBS</i>	5,917,791	6/1999	Tsuchiya et al.	—	—	<i>C</i>	
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION NO YES	
<i>MBS</i>	0 910 079	4/1999	Europe	—	—	x	
<i>MBS</i>	10-74356	3/1998	Japan	—	—	Abstract	
<i>MBS</i>	11-203691	7/1999	Japan	—	—	Abstract	
<i>MBS</i>	11-213530	8/1999	Japan	—	—	Abstract	
<i>MBS</i>	2000-315355	11/2000	Japan	—	—	Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER	<i>Michael S. Zalenga</i>			DATE CONSIDERED <b>6/15/04</b>			

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